





Power MOSFETS

PRELIMINARY DATASHEET

LM40018NHK8A

N-Channel
Enhancement Mode MOSFET

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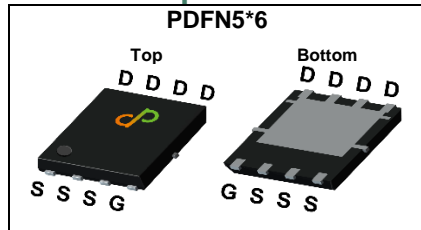


Quality Management Systems

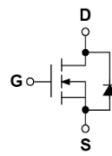
ISO 9001:2015 Certificate

N-Channel Enhancement Mode MOSFET

Pin Description



Symbol



Product Summary

Symbol	N-Channel	Unit
V_{DSS}	40	V
$R_{DS(ON)-Max}$	1.7	m Ω
ID	211	A

Feature

- Reliable and Rugged
- ROHS Compliant & Halogen-Free
- 100% UIS and Rg Tested

Applications

- Power Load Switch
- Battery Powered System

Ordering Information

Orderable Part Number	Package Type	Form	Shipping	Marking
LM40018NHNK8A	PDFN5*6	Tape & Reel	5000 / Tape & Reel	40018 □□□□□G

Note : □□□□□ = Lot code

Absolute Maximum Ratings (T_J=25°C Unless Otherwise Noted)

Symbol	Parameter	N-Channel	Unit	
V_{DSS}	Drain-Source Voltage	40	V	
V_{GSS}	Gate-Source Voltage	±20		
T_J	Maximum Junction Temperature	175	°C	
T_{STG}	Storage Temperature Range	-55 to 175	°C	
$I_{DM}^{①}$	Pulse Drain Current Tested	T _C =25°C	400	A
I_S	Diode Continuous Forward Current	T _C =25°C	124.5	A
I_D	Continuous Drain Current	T _C =25°C	211	A
		T _C =100°C	150	
P_D	Maximum Power Dissipation	T _C =25°C	115	W
		T _C =100°C	57.7	
$I_D^{②}$	Continuous Drain Current	T _A =25°C	34	A
		T _A =70°C	28.5	
$P_D^{③}$	Maximum Power Dissipation	T _A =25°C	3	W
		T _A =70°C	2.1	
$I_{AS}^{②}$	Avalanche Current, Single pulse	L=0.1mH	65	A
		L=0.3mH	46	
$E_{AS}^{②}$	Avalanche Energy, Single pulse	L=0.1mH	214	mJ
		L=0.3mH	316	

Thermal Characteristics

Symbol	Parameter	Rating	Unit	
$R_{\theta JC}$	Thermal Resistance-Junction to Case	Steady State	1.3	°C/W
$R_{\theta JA}^{③}$	Thermal Resistance-Junction to Ambient	Steady State	50	°C/W

Note ① : Max. current is limited by junction temperature.

Note ② : UIS tested and pulse width are limited by maximum junction temperature 175°C

Note ③ : Surface Mounted on 1in² FR-4 board with 1oz.

N-Channel Electrical Characteristics (T_J=25°C Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
Static Electrical Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _{DS} =250uA	40	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	V _{DS} =36V, V _{GS} =0V	-	-	1	uA
V_{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250uA	2	3	4	V
I_{GSS}	Gate Leakage Current	V _{GS} =±20V, V _{DS} =0V	-	-	±100	nA
R_{DS(ON)}^④	Drain-Source On-state Resistance	V _{GS} =10V, I _{DS} =20A	-	1.4	1.7	mΩ
gfs	Forward Transconductance	V _{DS} =5V, I _{DS} =10A	-	52.3	-	S
Dynamic Characteristics^⑤						
R_G	Gate Resistance	V _{GS} =0V, V _{DS} =0V, Freq.=1MHz	-	4.4	-	Ω
C_{iSS}	Input Capacitance	V _{GS} =0V, V _{DS} =20V, Freq.=1MHz	-	6788	-	pF
C_{oss}	Output Capacitance		-	605	-	
C_{rSS}	Reverse Transfer Capacitance		-	453	-	
t_{d(ON)}	Turn-on Delay Time	V _{GS} =10V, V _{DS} =20V, I _D =1A, R _{GEN} =6Ω	-	12.8	-	nS
t_r	Turn-on Rise Time		-	15	-	
t_{d(OFF)}	Turn-off Delay Time		-	313	-	
t_f	Turn-off Fall Time		-	100	-	
Q_g	Total Gate Charge	V _{GS} =4.5V, V _{DS} =20V, I _D =20A	-	80.5	-	nC
Q_g	Total Gate Charge	V _{GS} =10V, V _{DS} =20V, I _D =20A	-	113	-	
Q_{gs}	Gate-Source Charge		-	45.2	-	
Q_{gd}	Gate-Drain Charge		-	36	-	
Source-Drain Characteristics						
V_{SD}^④	Diode Forward Voltage	I _{SD} =10A, V _{GS} =0V	-	0.7	1.1	V
t_{rr}	Reverse Recovery Time	I _F =10A, V _R =20V	-	28	-	nS
Q_{rr}	Reverse Recovery Charge	di _F /dt=100A/μs	-	22.4	-	nC

Note ④ : Pulse test (pulse width≤300us, duty cycle≤2%).

Note ⑤ : Guaranteed by design, not subject to production testing.